TO: KSI/Scientific & Technical Information Division
Attention: Miss Winnie M. Morgan

FROM: GP/Office of Assistant General Counsel for Patent Matters

SUBJECT: Announcement of NASA-Owned U.S. Patents in STAR

In accordance with the procedures agreed upon by Code GP and Code KSI, the attached NASA-owned U.S. Patent is being forwarded for abstracting and announcement in NASA STAR.

The following information is provided:

U.S. Patent No. : 3,733,424

Government or Corporate Employee : U.S. Government

Supplementary Corporate Source (if applicable)

NASA Patent Case No. : LAR-10756-1

NOTE - If this patent covers an invention made by a corporate employee of a NASA Contractor, the following is applicable:

Pursuant to Section 305(a) of the National Aeronautics and Space Act, the name of the Administrator of NASA appears on the first page of the patent; however, the name of the actual inventor (author) appears at the heading of column No. 1 of the Specification, following the words "... with respect to an invention of ..."

Elizabeth A. Carter
Enclosure
Copy of Patent cited above
An electronic strain level counter for obtaining structural strain data on in-flight aircraft. The device counts the number of times the strain at a point on a structural member of the aircraft exceeds each of several preset levels. A dead band is provided at each level to prohibit the counting of small strain variations around a given preset level.

2 Claims, 3 Drawing Figures
FIG. 2

FIG. 3

OUTPUT VOLTAGE

DEAD BAND

INPUT VOLTAGE
ELECTRONIC STRAIN-LEVEL COUNTER

ORIGIN OF THE INVENTION

The invention described herein was made by employees of the United States Government and may be manufactured and used by or for the Government for governmental purposes without the payment of any royalties thereon or therefor.

BACKGROUND OF THE INVENTION

The invention relates generally to strain measurements and more specifically concerns a device for counting the number of times that the strain in a structural member exceeds each of several preselected levels.

Structural fatigue assessment of in-service aircraft is based primarily on visual and x-ray inspection procedures. An electronic device which counts the number of times the strain at a point in a structural member exceeds each of several preset levels is needed to augment these established procedures. The complexity of the structural-fatigue assessment of aircraft does not allow structural-lifetime prediction to be based entirely on data generated by strain-level counters. However, use of the strain counters in a fleet of aircraft can yield a statistical-data body on the number and severity of the in-service structural strains. Based on this information, a graduated scale of aircraft-use severity can be generated and used to aid in scheduling inspection and maintenance. In addition, correlation of the data with observed fatigue failures might aid in general fatigue assessment of aircraft of the same type.

In the past, devices such as extensometers and mechanical scratch gages have been used to accomplish the strain level counter function. The disadvantage of the extensometer approach is that a long gage length is required to obtain high sensitivity. The primary disadvantage of the mechanical scratch gage is that the data output is an analog scratch waveform on a small metallic disk which results in difficult data reduction.

It is therefore the primary object of this invention to provide a simple, accurate and reliable electronic device which counts the number of times the strain at a point in a structural member exceeds each of several preselected levels. Another object of the invention is to provide an adjustable dead band around each of the preselected levels to prohibit the counting of small strain variations due to flexural oscillations around the preselected levels.

SUMMARY OF THE INVENTION

The strain level counter that constitutes this invention counts the number of times the strain at a point in a structural member exceeds each of several preset levels. By using hysteresis, a dead band is provided at each level so that after the strain exceeds a given level and a count is registered, the strain must decrease below the dead band and then increase again before another count is registered. The adjustable dead band prohibits the counting of small strain variations due to flexural oscillations around a given level.

In the present invention, each of several separate counters counts the number of times the strain exceeds a different preselected level. The system uses a metallic resistance strain gage as the sensor, a.c. bridge excitation obtained from an operational amplifier with a closed loop gain that is determined by the feedback resistor and the output impedance of the bridge. The output of the a.c. bridge is a pulse train with an amplitude proportional to the strain. If there is no strain on the bridge, the bridge is balanced and hence there is no output. If a strain is applied to the bridge, then the bridge becomes unbalanced and a series of pulses are produced at the output whose amplitudes are proportional to the strain being applied to the bridge. The output of bridge 11 is amplified by an a.c. coupled amplifier 13 which is of the well known resistance type strain gage which produces an output signal whose amplitude is proportional to the strain. The strain gage bridge 11 is excited by an a.c. coupled amplifier 12 with a frequency of approximately 90 hertz and a pulse duration of approximately 0.5 millisecond. The pulse duration of the multivibrator is long enough to allow all system transients to decay before the level detectors are enabled. Hence, the output of strain gage bridge 11 is a series of pulses whose amplitudes are proportional to the strain. If there is no strain on the bridge, the bridge is balanced and hence there is no output. If a strain is applied to the bridge 11, then the bridge becomes unbalanced and a series of pulses are produced at the output whose amplitudes are proportional to the strain being applied to the bridge. The output of bridge 11 is amplified by an a.c. coupled amplifier 13 which is an operational amplifier with a closed loop gain that is determined by the feedback resistor and the output impedance of the bridge. The output of amplifier 13 is capacitively coupled through a capacitor 14 to level detectors 15, 15a, 15b so that the d.c. drift does not affect the system performance so long as it is not severe enough to cause saturation. Only three level detectors are shown in FIG. 1; however, as many of these level detectors as desired can be used. In addition to exciting bridge 11, astable multivibrator 12 is also applied to the strobe-pulse generator 16. Strobe pulse generator 16 is a one-shot multivibrator that is triggered on by the asta-
ble multivibrator 12 at the beginning of an excitation pulse and switches off to enable the level detectors 15, 15a and 15b. Each of the level detectors has an adjustable d.c. reference source which is adjusted to a different preselected level. This level is compared with the output from amplifier 13 and when the output of the amplifier becomes greater the corresponding drive circuit 17, 17a or 17b produces a pulse which is counted by the corresponding counter 18, 18a or 18b. Drive circuit 17, 17a and 17b are one-shot multivibrators which produce a voltage pulse or 20 milliseconds duration to drive the electromechanical counters 18, 18a and 18b. Each time the strain on the strain gage bridge 11 exceeds the value set into one of the level detectors the corresponding counter registers a count. In order to keep the level detectors from causing its corresponding counter to register a count for small changes around the preset level of the level detector, each of the level detectors is provided with hysteresis which will be described in detail in FIG. 2.

Referring now to FIG. 2, there is shown a schematic drawing of one of the level detectors in FIG. 1. The pulses from amplifier 13 in FIG. 1 are applied through the capacitor 14 to terminal 20 which is connected to the inverting input (−) of a comparator 21. The amplitudes of these pulses are compared with a d.c. voltage reference (Vr) 22 which is applied through a variable resistor 23 to the comparator 21. A different Vr is used in each level detector and variable resistor 23 is used to set the hysteresis in each level detector. The output of comparator 21 is applied to a D-type flip-flop 24 which also has the pulses from strobe pulses generator 16 applied to it through a terminal 25. When a strobe input on terminal 25 changes from a low binary state to a high binary state the output of flip-flop 24 assumes the same binary state as the comparator output. The output of flip-flop 24 is applied through a resistor 26 to the comparator 21. The output of flip-flop 24 is also applied through a terminal 27 to one of the drive circuits.

The function of the level detector circuitry is to compare the amplitude of the pulse from the amplifier with a preset d.c. voltage level at each positive transition of the strobe input. Positive feedback from the output of the flip-flop to the noninverting input (+) of the comparator through resistor 26 enables the circuitry to have hysteresis. The voltage on the noninverting input of the comparator is denoted by Vr and is described by

\[ V = V_0 + \frac{R_{26}}{R_{23}} (V_{r} - V_0) \]

where \( V_0 \) is the voltage of the d.c. voltage reference 22, \( V_r \) is the output voltage of the flip-flop 24, \( R_{23} \) is the resistance in ohms of resistor 23 and \( R_{26} \) is the resistance in ohms of resistor 26. The comparator 21 output is connected to flip-flop 24 so that when the strobe input changes from a low binary state to a high binary state the output of the flip-flop assumes the same binary state as the comparator output. The flip-flop is enabled after all transients of the signal pulse have decayed.

With zero strain on the resistive strain gage 11, the amplifier 13 output signal level during enabling is zero and the outputs of both the comparator 21 and the flip-flop 24 are high. When the output of the flip-flop is high, the voltage of noninverting input \( V_r \) of the comparator is defined to be the upper threshold voltage \( V_1 \) (see FIG. 3) and is described by

\[ V_1 = V_r + \frac{R_{26}}{R_{23}} (V_{r,\text{max}} - V_1) \]
the strain must decrease below the dead band and then increase again before another electrical signal is produced; and means associated with each of said level detector means for counting said electrical signals whereby the count on each of said counting means is the number of times the strain exceeds the preset amplitude in the corresponding level detector means.

2. An electronic strain level counter according to claim 1 wherein said means for producing an electrical signal each time the amplitudes of one of the electrical pulses indicative of strain exceeds said preset amplitude and for providing a dead band is a D-type flip-flop with means for adding the output of the flip-flop to said preset amplitude.